##20 RESULTION BO 10576453 : GAU: 4118

FORM PTO-1449 (REV. 7-80) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE ATTY DOCKET NO. 5005.1107 To be assigned

LIST OF PRIOR ART CITED BY APPLICANT

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GROUP 3742

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	A01	4,741,043	Apr. 26, 1988	Bacus	382	6	
	A02	5,843,657	Dec. 1, 1998	Liotta et al.	435	6	
	A03	5,998,129	Dec. 7, 1999	Schütze et al.	435	4	
	A04	2002/0090122	Jul. 11, 2002	Baer et al.	382	128	
	A05	2002/0164678	Nov. 7, 2002	Ganser et al.	435	40.5	
	A06	6,787,301	Sep. 7, 2004	Ganser et al.	435	4	
	A07	6,907,798	Jun. 21, 2005	Ganser et al.	73	864.41	
	A08	5,031,099	Jul. 9, 1991	Kettler	364	413.08	
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	A10	6,713,264	Mar. 30, 2004	Luttermann et al.	435	7.1	<u> </u>
	A11	6,991,714	Jan. 31, 2006	Gauss et al.	204	462	

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				i	i	YES	NO	
A12	WO 01/73398	Oct. 4, 2001	WO-WIPO			See Abstract		
A13	DE 100 18 251	Oct. 25, 2001	DE-Germany			Corresponds to US 6,907,798		
A14	DE 100 43 506	Dec. 6, 2001	DE-Germany			Corresponds to US 6,787,301		
A15	DE 196 36 074	Mar. 26, 1998	DE-Germany			See Intl. Search Report for PCT/EP2004/052600; see English Abstract		
A16	DE 695 10 925	Feb. 17, 2000	DE-Germany			Corresponds to US 5,843,644		
A17	DE 42 11 904	Nov. 19, 1992	DE-Germany			See Abstract		
A18	DE 196 29 141	Apr. 16, 1998	DE-Germany			Corresponds to US 6,713,264		
A19	DE 38 36 716	May 3, 1990	DE-Germany			Corresponds to US 5,031,099		
 A20	DE 198 15 400	Oct. 14, 1999	DE-Germany	1		Corresponds to US 6,991,714		

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	A21	International Search Report for PCT/EP2004/052600 (4 pages)
	A22	P.A.L.M. Microlaser Technologies: "PALM MicroBeam IP-MS + Metafer P, February 2003 (4 pages)
	A23	ARCTURUS: "Laser Capture Microdissection (LCM) Systems", XP-002315059 (6 pages)
	A24	B. J. SCHACHTER et al.: "Some Experiments in Image Segmentation by Clustering of Local Feature Values", XP-002269476, Pattern Recognition, Vol. 11, Pattern Recognition Society, Pergamon Press Ltd., Great Britain, pp. 19-28

EXAMINER

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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.